



ITRS & e-Manufacturing Report

Date: Tuesday, December 4, 8:30-11:55
Place: 2F Royal Crystal, Hotel Le Port Kojimachi

**Program Co-chairs: Michio Honma / NEC Corp.
Shigeru Kobayashi / Semiconductor Leading Edge Technologies, Inc. (Selete)**

ITRS Update

Greetings Karl Gartland (IBM)
2001 International Technology Roadmap for Semiconductors (ITRS)
Factory Integration Attributes and Drivers for E-Manufacturing
Michio Honma (NEC)/Jeff Pettinato (ISMT)

EEC Guidelines Announcement & The Latest Status of e-Diagnostics

EEC Guideline Phase 2.0 Rollout – An Overview
Brad Van Eck (ISMT)
EEC Phase 2.0 Guideline Rollout Kinji Mokuya (Selete)/Blaine Crandell (TI)

e-Diagnostics Latest News Harvey Wohlwend (ISMT)

e-Diagnostics Security Update Dave Bloss (Intel)

Security Operation Consideration at Device Makers Kanji Morikawa (Hitachi)

JEITA's Reticle Data Management Guidelines Activity Report Nobuyuki Iriki (Hitachi)

SEMICON Japan 2001

e-Manufacturing Workshop

SEMICON Japan 2001 e-Manufacturing Workshop

Date: Tuesday, December 4, 12:45-17:10
Place: 2F Royal Crystal, Hotel Le Port Kojimachi

e-Manufacturing is moving for business Michio Honma (NEC)

Business Interest of e-Manufacturing Giichi Inoue (Toshiba)

Business Model Study Yasutsugu Usami (Hitachi)

EEC Standards Approach Lance Rist (ISMT)

IEE Task Force Activity Report Tomoyuki Masui (Selete)

Basic EE Data Utilization Examples (with emphasis on 200mm tools)
Shigeru Kobayashi (Selete)

EES Capability Implementation Approach for 200mm Tools with improved Data Resolution
Eiji Suzuki (System V)

IT Application to Semiconductor Factory from Construction to Fab Operation
Norihisa Yuzawa (Shinryo)

APC/EES Systems and Applications Atsuhiko Kato (KLA-Tencor)

e-Manufacturing & APC Koji Kitajima (Toshiba)

Summary Giichi Inoue (Toshiba)